

**Search Notes**

Application/Control No.

10/672,672

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under  
Reexamination

YOSHIDA ET AL.

Art Unit

1745

**SEARCHED**

Class	Subclass	Date	Examiner
429	12	9/22/2006	DWY
429	34	9/22/2006	DWY
429	35	9/22/2006	DWY
429	36	9/22/2006	DWY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	9/22/2006	DWY